WEST Search History

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	Hide Items	Restore	Clear	Cancel
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DATE: Sunday, February 04, 2007

Hide?	<u>Set</u> Name	Query	<u>Hit</u> Count
	DB=PC	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=ADJ	
	L15	L14 not l12	74
	L14	((average or surface) near2 roughness) and gas diffusion (layer or electrode or material or substance)	97
	L13	L12 not 13	9
	L12	((average or surface) near2 roughness) same gas diffusion (layer or electrode or material or substance)	23
	DB=EB	PAB; PLUR=YES; OP=ADJ	
	L11	WO-200289240-A1.did.	0
	L10	WO-200289240-A1.did.	0
	DB=PC	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=ADJ	
	L9	WO-200289240-A1.did.	1
	L8.	WO-2002089240-A1.did.	0
DB=EPAB; PLUR=YES; OP=ADJ			
	L7	WO-2002089240-A1.did.	0
	L6	WO-200289240-A1.did.	0
	DB=PC	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR = YES; OP = ADJ	
	L5	US-20040137303-\$.did.	2
	L4	L3 not 11	11
	L3	(surface near2 roughness) with gas diffusion (layer or electrode or material or substance)	14
	L2	JP-2003036860-\$.did.	2
Ö	L1	(average near2 roughness) with gas diffusion (layer or electrode or material or substance)	3

END OF SEARCH HISTORY

Refine Search

Search Results -

Term	Documents
(14 NOT 12).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	74
(L14 NOT L12).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	74

US Pre-Grant Publication Full-Text Database
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US OCR Full-Text Database
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IBM Technical Disclosure Bulletins

Search:

Database:

L15		Refine Search
Recall Text	Clear	Interrupt

Search History

DATE: Sunday, February 04, 2007 Purge Queries Printable Copy Create Case

Set Name side by side	Query	<u>Hit</u> Count	<u>Set</u> <u>Name</u> result set
DB=I	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		
<u>L15</u>	L14 not 112	74	<u>L15</u>
<u>L14</u>	((average or surface) near2 roughness) and gas diffusion (layer or electrode or material or substance)	97	<u>L14</u>
<u>L13</u>	L12 not 13	9	<u>L13</u>
<u>L12</u>	((average or surface) near2 roughness) same gas diffusion (layer or electrode or material or substance)	23	<u>L12</u>
DB=B	EPAB; PLUR=YES; OP=ADJ		
<u>L11</u>	WO-200289240-A1.did.	0	<u>L11</u>
<u>L10</u>	WO-200289240-A1.did.	0	<u>L10</u>
DB=B	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		
<u>L9</u>	WO-200289240-A1.did.	1	<u>L9</u>
<u>L8</u>	WO-2002089240-A1.did.	0	<u>L8</u>

DB=B	EPAB; PLUR=YES; OP=ADJ		
<u>L7</u>	WO-2002089240-A1.did.	0	<u>L7</u>
<u>L6</u>	WO-200289240-A1.did.	0	<u>L6</u>
DB=B	PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		
<u>L5</u>	US-20040137303-\$.did.	2	<u>L5</u>
<u>L4</u>	L3 not 11	11	<u>L4</u>
<u>L3</u>	(surface near2 roughness) with gas diffusion (layer or electrode or material or substance)	14	<u>L3</u>
<u>L2</u>	JP-2003036860-\$.did.	2	<u>L2</u>
<u>L1</u>	(average near2 roughness) with gas diffusion (layer or electrode or material or substance)	3	<u>L1</u>

END OF SEARCH HISTORY